



TestForum 2024

Clarion Hotel, Helsinki, Finland
November 26th - 27th, 2024

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Test Forum 2024 Local Organizer

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Call for Papers / Presentations

The 2-day TestForum 2024, the 24th event in the series, is the major event for Test professionals in the Nordic area and the Baltic states. Every year the TestForum is attended by key people from the industry's test community as well as by international vendors of test and measurement equipment and solutions.

This year the event will take place in Helsinki.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2024, which includes (but is not limited to) the following topics:

- *Functional Test*
- *Boundary Scan*
- *Embedded Instruments*
- *RF Testing*
- *AOI / AXI / SPI*
- *ICT / Flying Probe*
- *Test economics*
- *Power Test/ Battery Test*
- *Fixturing/Interfaces*
- *How to Utilize R&D measurements, fault and test cases for production.*
- *Future technology trends and test challenges*
- *Best practices in manufacturing test*
- *Utilizing Semiconductor Test solutions at board test.*
- *Board test SW, BIST, diagnostics*
- *Quality methods and tools*
- *Product Validation Test*
- *Preventive test / Prognostics*
- *Design to Test transfer / Design for Test*
- *ESD*
- *Test efficiency and optimization*
- *Data acquisition / collection / analysis*

Submissions

TestForum seeks full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products.

Proceedings

The accepted contributions of authors that wish to provide the corresponding materials will be delivered in electronic format at the Nordic Test Forum event.

The Format of the Event

- The event format will be a two-day workshop and a small exhibition attached to it.
- November 25th in the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- In the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- Abstract submission:
- Notification of acceptance:
- Conference registration
- Presentation slides:

28th June 2024

9th August 2024

16th September 2024

3rd November 2024

Visit the NTF web pages at:

<http://www.nordicestforum.org>

Further Information and Submissions

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